

Amendments to the Claims:**In the Claims:**

Please CANCEL claims 1 and 5-31 without prejudice, AMEND claims 2 and 3 as follows, and ADD new claims 32-34, such that the pending claims will read as follows:

Claim 1 (Canceled).

Claim 2 (Currently amended): A method of testing an electronic device on a wafer, comprising:

providing an electronic device for use in an optical communications system after the electronic device is packaged with an associated photo detector;

providing a test photo detector having electrical characteristics similar to the associated photo detector; and

prior to packaging the electronic device with the associated photo detector, detecting defects in the electronic device using the test photo detector by:

generating an optical test signal;

providing the optical test signal to [[a]]
the test photo detector; and

supplying an electrical output of the test
photo detector to the electronic device on the wafer.

Claim 3 (Currently amended): The method of claim 2, wherein the optical test signal is provided to the test photo detector via a variable optical attenuator.

Claim 4 (Original): The method of claim 2, wherein the optical test signal is generated in accordance with a signal generated by a test controller.

Claims 5-31 (Canceled).

Claim 32 (New): The method of claim 2 wherein detecting defects in the electronic device includes using the test photo detector to perform a wafer-level test.

Claim 33 (New): A method comprising:

- providing an electronic integrated circuit (IC) for use in an optical communications system after the electronic IC is packaged with an associated photo detector;
- performing a wafer-level test of the electronic IC using a test photo detector having characteristics similar to the associated photo detector; and
- using the wafer-level test to detect defects in the electronic IC prior to packaging the electronic IC with the associated photo detector.

Claim 34 (New): The method of claim 33 wherein performing the wafer-level test includes:

- generating an optical test signal;
- providing the optical test signal to the test photo detector; and
- supplying an electrical output of the test photo detector to the electronic IC.